

Application/Control No.	Applicant(s)/Patent under Reexamination
10/646,470	CHIEN ET AL.
Examiner	Art Unit

Nashaat T. Nashed, Ph. D.

1656

SEARCHED					
Subclass	Date	Examiner			
•					
		÷			
	,				
	1	Subclass Date			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	3 & residues SEQ ID NO:1 ding fil	8/24/2007	NASH	

(INCLUDING SEARCH	T	,
	DATE	EXMR
WEST Search, enclosed.	9/7/2007	NASH
SEQ ID NO: 3 and residues 114-331 of SEQ ID NO:1 in issued patent and published application.	8/24/2007	NASH
· · · · · · · · · · · · · · · · · · ·		3
·		